

PART NUMBER 0830L-21A

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PRODUCT DATASHEET

230 nm MathBox

ITEM NAME 830 NM SLM LASER (VBG DIODE; FREE-SPACE)

DESCRIPTION

Miniature 830 nm diode lasers are popular in Raman, fluorescence as excitation sources, or in NIR spectroscopy as a light source. The self-contained package allows for the most convenient integration into handheld devices. Matchbox modules feature high power and spectrum stability.

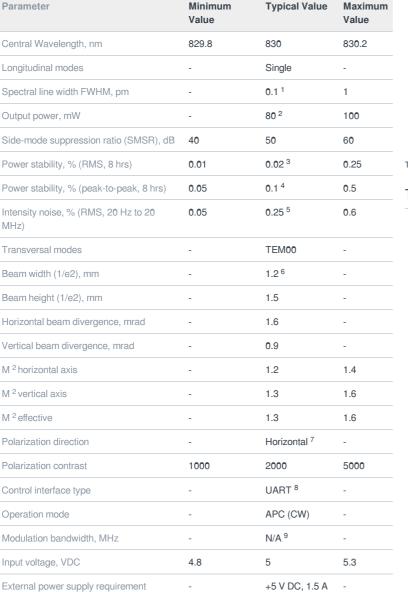
Note:

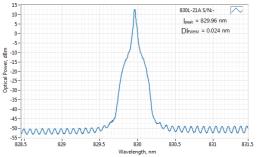
In optical systems with strong back-reflections (e.g. more than 10%), the laser must be protected by using an optical isolator with at least 20 dB isolation. Typical applications include interferometry, confocal microscopy (especially working with reflective samples), etc. Failure to comply with these requirements will render the warranty void for cases of COD (Catastrophic Optical Damage) of laser diode facets.

SPECIFICATIONS

Specifications updated: 4 May 2021

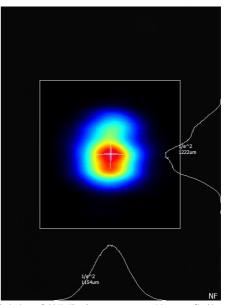
TYPICAL SPECTRUM





Typical spectrum of 0830 nm diode laser. Measured with 20 pm resolution.

TYPICAL NEAR FIELD



Typical near field (0.45 m from output aperture) beam profile. Noncircularized beam of a 0830 nm direct diode laser.

Dimensions, mm	-	50 x 30 x 18 ¹⁰	-
Beam height from the base, mm	9.9	10.4	10.9
Heat-sinking requirement, °C/W	-	1	-
Optimum heatsink temperature, °C	15	20	30
Warm up time, mins (cold start)	0.2	1	2
Temperature stabilization	-	Internal TEC	-
Overheat protection	-	Yes	-
Storage temperature, °C (non- condensing)	-10	-	50
Net weight, kg	0.1	0.12	0.14
Max. power consumption, W	0.4	2	10
Warranty, months (op. hrs)	-	14 (10000) ¹¹	-
RoHS	-	Yes	-
CE compliance	-	- General Product Safety Directive (GPSD) 2001/95/EC - (EMC) Directive 2004/108/EC	-
Laser Safety Class	-	3B	-
OEM lasers are not compliant with	-	IEC60825- 1:2014 (compliant using additional accessories)	-
Country of origin	-	Lithuania	-

¹ Measured with a scanning Fabry-Perot interferometer having 7.5 Mhz resolution, with scanning frequency of about 10 Hz. Interferometer testing is not provided for each laser being manufactured, the standard test is OSA measurement with 10-20 pm resolution instead.

² The output power of SLM lasers shall not be tuned and SLM performance is not guaranteed at power ratings other than factory preset. However, the power setting capability is not disabled. External attenuators are recommended instead.

 3 The long term power test is carried out at constant laser body temperature (+/-0.1 °C) using an optical power meter with an input bandwidth of 10 Hz. The actual measurement rate has a period of about 20 seconds to 1 minute.

⁴ The long term power test is carried out at constant laser body temperature (+/-0.1 °C) using an optical power meter with an input bandwidth of 10 Hz. The actual measurement rate has a period of about 20 seconds to 1 minute. ⁵ Noise level is measured with a fast photodiode connected to an oscilloscope. The overall system bandwidth is from 2 kHz to 20 MHz.

 $^{6}\,\textsc{Beam}$ width and height are measured at 0.45 m from output aperture.

⁷ For lasers without integrated optical isolators.

⁸ Break-out-boxes AM-C8 and AM-C3 can be used for conversion of UART communication to either USB or RS232.

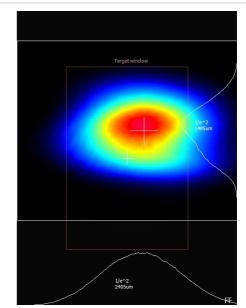
⁹ SLM lasers shall not be modulated - use external modulators instead.

¹⁰ Excluding control interface pins and an output window/fiber assembly.

¹¹ Whichever occurs first. The laser has an integrated operational hours counter.

Note: Product specifications are subject to change without prior notice to improve reliability, function or design or otherwise.

TYPICAL FAR FIELD



Typical far field (1 m from output aperture) beam profile. Non-circularized beam of a 0830 nm direct diode laser.

DRAWING

